

<b>Notice of References Cited</b>	Application/Control No. 10/580,515	Applicant(s)/Patent Under Reexamination WANG ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0154893	10-2002	Tanaka et al.	386/95
*	B	US-2002/0107973	08-2002	Lennon et al.	709/231
*	C	US-2003/0014767	01-2003	Stumphauzer, William C. II	725/131
*	D	US-2003/0049029	03-2003	Murakami et al.	396/429
*	E	US-6,810,441	10-2004	Habuto et al.	710/20
*	F	US-2002/0016776	02-2002	Chu et al.	705/52
*	G	US-6,408,301	06-2002	Patton et al.	707/102
*	H	US-2001/0042107	11-2001	Palm, Stephen R.	709/218
*	I	US-6,584,459	06-2003	Chang et al.	707/3
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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